Search Notes		
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/676,258	MIYANO ET AL.	
Examiner	Art Unit	
B. Chen	1762	

SEARCHED			
Class	Subclass	Date	Examiner
427	595 582 586	9/15/2005	вс

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SI (INCLUDIN	EARCH NOTES G SEARCH STRATEGY	')
	DATE	EXMR
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